

AMENDMENTS TO THE CLAIMS

This listing of claims replaces all prior listing of claims in this application

Claims 1-36 (Canceled).

37. (Currently amended) An electron microscope comprising:

a support for supporting a specimen;

a deflector for deflecting an electron beam to the specimen to form images;

an image pickup device for obtaining the images; and

a processor coupled to the image pickup device being programmed for observing the specimen in a field of view of the electron microscope, said programming comprising the act of:

calculating a degree of coincidence of images obtained by differential electro-optical conditions of the electron microscope;

determining whether the image of the field of view is suitable or not for an observation based on calculated degree; and

moving the field of view to a next position when the image of the field of view is determined to be not suitable.

38. (Currently amended) An electron microscope comprising:

a support for supporting a specimen;

a deflector for deflecting an electron beam to the specimen to form images;

an image pickup device for obtaining the images; and

a processor coupled to the image pickup device being programmed for observing the specimen in a field of view of the electron microscope, said programming comprising the act of:

calculating a phase only correlation or a phase-amplitude correlation of images obtained by differential electro-optical conditions of the electron microscope;

determining whether the image of the field of view is suitable or not for an observation based on calculated degree; and

moving the field of view to a next position when the image of the field of view is determined to be not suitable.

39. (Currently amended) A method of observing a specimen in a field of view of an electron microscope comprising the acts of:

deflecting an electron beam to the specimen to form images;

acquiring said images from the specimen using an image pickup device; and

observing the images in a field of view of the electron microscope using programming from a processor, said programming including the acts of:

calculating a degree of coincidence of images obtained by differential electro-optical conditions of the electron microscope;

determining whether the image of the field of view is suitable or not for an observation based on calculated degree; and

moving the field of view to a next position when the image of the field of view is determined to be not suitable.